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*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
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## FOREIGN PATENT DOCUMENTS

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		DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO	ABSTRACT
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	/N.W./	AK	T. Yamazaki et al., "Slit Structure as a Countermeasure for the Thermal Deformation of a Metal Mask," Japanese Journal of Applied Physics, Vol. 40, Part 1, No. 12, December 15, 2001, pp. 7170-7173.		
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EXAMINER	DATE CONSIDERED			
/Natalie Walford/	04/25/2008			
*EVANUALED. In the formula considered whether or not distance is in conformance with MPEP 609. Draw line through				

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